Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	178	257/778.ccls. and (mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:50
L2	91	L1 and (@ad<"19991110")	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 13:58
L3	59	257/777.ccls. and (mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 13:57
L4	31	L3 and (@ad<"19991110")	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 13:57
L5	23	L4 not L2	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 13:55
L6	6	257/612.ccls. and (mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 13:57
L7	178	438/612.ccls. and (mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:01
L8	76	L7 and (@ad<"19991110")	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:02
פ	54	L8 and (ball or bump or solder)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:10

			, 		<u> </u>	 1
L10	139	438/108.ccls. and (mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:04
L11	43	L10 and (@ad<"19991110")	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25:14:08
L12	35	L11 not L9	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:02
L14	8378	((mask and (position or orientation or placement)) same (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:07
L15	3844	((mask and (position or orientation or placement)) with (pad or land or trace or pattern)) and (stress or tension or strain or pressure)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:07
L16	926	L15 and (@ad<"19991110") and (chip or die)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:52
L17	346	L16 and (interconnect or ball or bump or solder)	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:19
L18	9	("6268568").URPN.	USPAT	OR	OFF	2005/02/25 14:38
L19	11	("5170931" "5351393" "5484963" "5539156" "5579207" "5859474" "5875102" "5894984" "6037547" "6133134" "6143991").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/02/25 14:39
L20	665	(mask same (pad or land or trace or pattern)) and (stress or tension or strain or pressure) and ((offset or elliptical or noncircular or (non near circular)) with (mask or opening))	USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/25 14:51

L21	157	L20 and (@ad<"19991110") and (chip or die)	USPAT; USOCR; EPO; JPO; DERWENT;	OR	OFF	2005/02/25 14:57
L22	17	("4391034");URPN.	IBM_TDB USPAT	OR	OFF	2005/02/25 15:01